

COMPLIANT

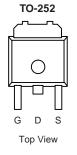
5N95K5-VB TO252 Datasheet

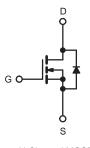
N-Channel 900 V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	900			
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	2.7		
Q _g (Max.) (nC)	200			
Q _{gs} (nC)	24			
Q _{gd} (nC)	110			
Configuration	Single			

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





N-Channel MOSFET

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	900	V	
Gate-Source Voltage			V _{GS}	± 20		
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	la la	2.0	А	
Continuous Drain Gurrent		T _C = 100 °C	ID ID	1.5		
Pulsed Drain Current ^a			I _{DM}	8.0		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	470	mJ	
Repetitive Avalanche Current ^a			I _{AR}	4.8	A	
Repetitive Avalanche Energy ^a			E _{AR}	19	mJ	
Maximum Power Dissipation	T _C =	25 °C	PD	120	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d		
Mounting Torque	6-32 or M3 screw			10	lbf · in	
Mounting Torque				1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50$ V, starting $T_J = 25$ °C, L = 23 mH, $R_g = 25 \Omega$, $I_{AS} = 7.8$ A (see fig. 12). c. $I_{SD} \le 7.8$ A, dl/dt ≤ 140 A/µs, $V_{DD} \le 600$ V, $T_J \le 150$ °C. d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

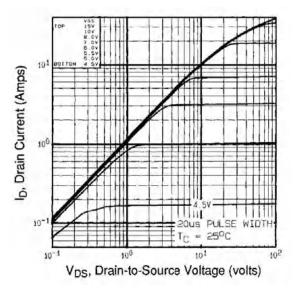
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THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	TYP.		MAX.		UNIT		
Maximum Junction-to-Ambient	R _{thJA}	- 40 0.24 -			°C/W			
Case-to-Sink, Flat, Greased Surface	R _{thCS}							
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.65						
		. N						
SPECIFICATIONS ($T_J = 25 \text{ °C}, u$		1			[T	1	ł
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static		1					1	1
Drain-Source Breakdown Voltage	V _{DS}		= 0 V, I _D =		900	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$		e to 25 °C,		-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =	= 800 V, V _G	_{is} = 0 V	-	-	100	μA
	-255	$V_{DS} = 640 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 125 ^{\circ}\text{C}$		-	-	500	μ, ,	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V			-	2.7	-	Ω
Forward Transconductance	g fs	$V_{DS} =$: 100 V, I _D :	= 1.7 A ^b	5.6	-	-	S
Dynamic								
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1.0 MHz, see fig. 5		-	1800	-	pF	
Output Capacitance	C _{oss}			-	500	-		
Reverse Transfer Capacitance	C _{rss}			-	290	-		
Total Gate Charge	Qg				-	-	200	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 1.8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b		-	-	24	nC
Gate-Drain Charge	Q _{gd}	-	3001	ig. o and to	-	-	110	1
Turn-On Delay Time	t _{d(on)}				-	19	-	-
Rise Time	t _r		= 400 V, I _D :		-	38	-	
Turn-Off Delay Time	t _{d(off)}	$\vec{R}_g = 6.2 \Omega, \vec{R}_D = 52 \Omega$ see fig. 10^b		-	120	-	ns	
Fall Time	t _f			-	39	-		
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	nH	
Internal Source Inductance	L _S			-	13	-		
Drain-Source Body Diode Characteristic	s							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	A	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21		
Body Diode Voltage	V _{SD}	$T_{J} = 25 \text{ °C}, I_{S} = 1.8 \text{ A}, V_{GS} = 0 \text{ V}^{b}$		-	-	1.8	V	
Body Diode Reverse Recovery Time	t _{rr}	T.=	25 °C. I⊧ =	1.8 A.	-	650	980	ns
Body Diode Reverse Recovery Charge	Q _{rr}	$T_J = 25 \ ^{\circ}C, I_F = 1.8 \ A,$ dl/dt = 100 A/µs ^b		-	3.8	5.7	μC	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_Γ						

Notes

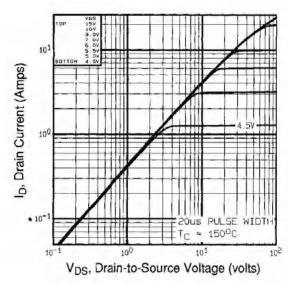
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)







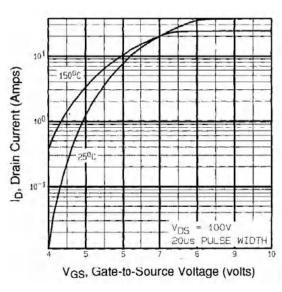
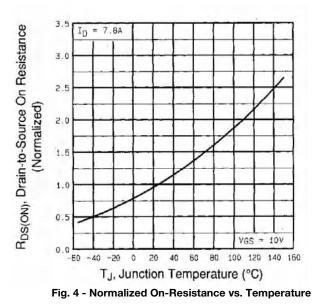


Fig. 3 - Typical Transfer Characteristics





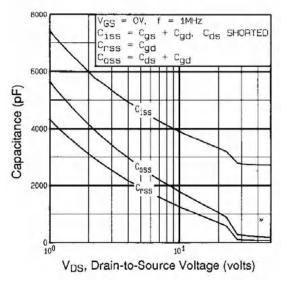


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

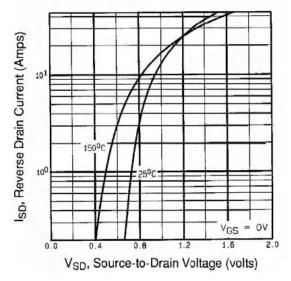


Fig. 7 - Typical Source-Drain Diode Forward Voltage

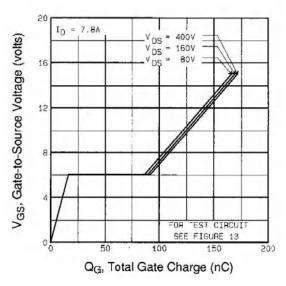
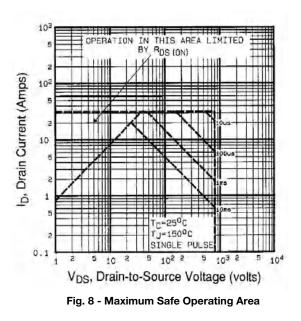


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





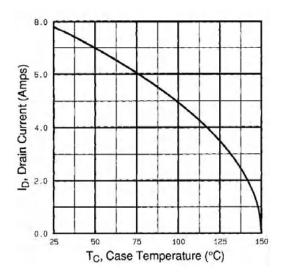


Fig. 9 - Maximum Drain Current vs. Case Temperature

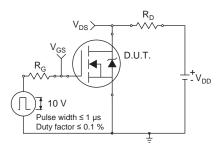


Fig. 10a - Switching Time Test Circuit

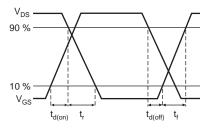


Fig. 10b - Switching Time Waveforms

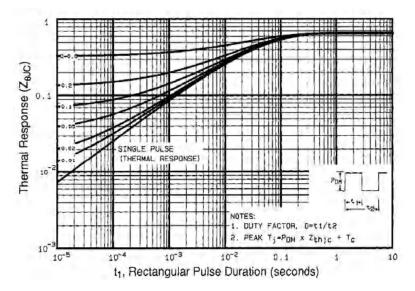


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



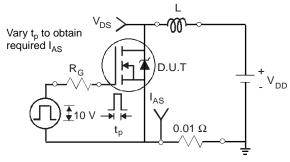


Fig. 12a - Unclamped Inductive Test Circuit

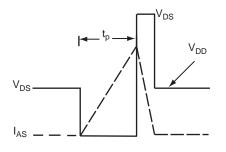


Fig. 12b - Unclamped Inductive Waveforms

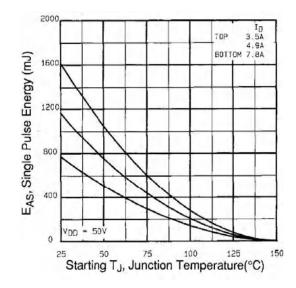


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

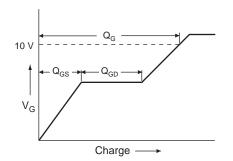


Fig. 13a - Basic Gate Charge Waveform

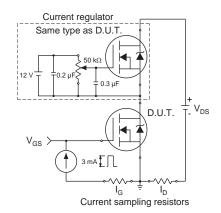
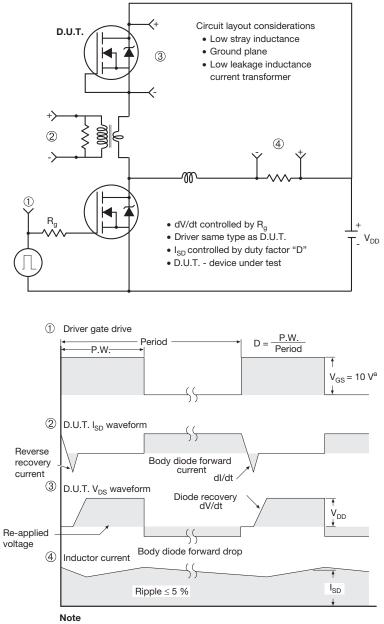


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

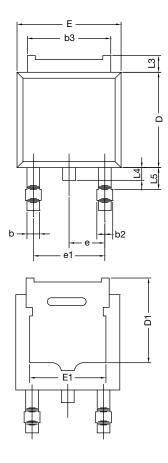


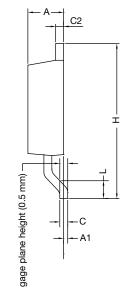
a. $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel



TO-252AA CASE OUTLINE





	MILLIN	METERS	INCHES			
DIM.	MIN.	MAX.	MIN.	MAX.		
А	2.18	2.38	0.086	0.094		
A1	-	0.127	-	0.005		
b	0.64	0.88	0.025	0.035		
b2	0.76	1.14	0.030	0.045		
b3	4.95	5.46	0.195	0.215		
С	0.46	0.61	0.018	0.024		
C2	0.46	0.89	0.018	0.035		
D	5.97	6.22	0.235	0.245		
D1	5.21	-	0.205	-		
E	6.35	6.73	0.250	0.265		
E1	4.32	-	0.170	-		
Н	9.40	10.41	0.370	0.410		
е	2.28 BSC		0.090 BSC			
e1	4.56 BSC		0.180 BSC			
L	1.40	1.78	0.055	0.070		
L3	0.89	1.27	0.035	0.050		
L4	-	1.02	-	0.040		
L5	1.14	1.52	0.045	0.060		
ECN: X12-0247-Rev. M, 24-Dec-12 DWG: 5347						

Note

• Dimension L3 is for reference only.



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